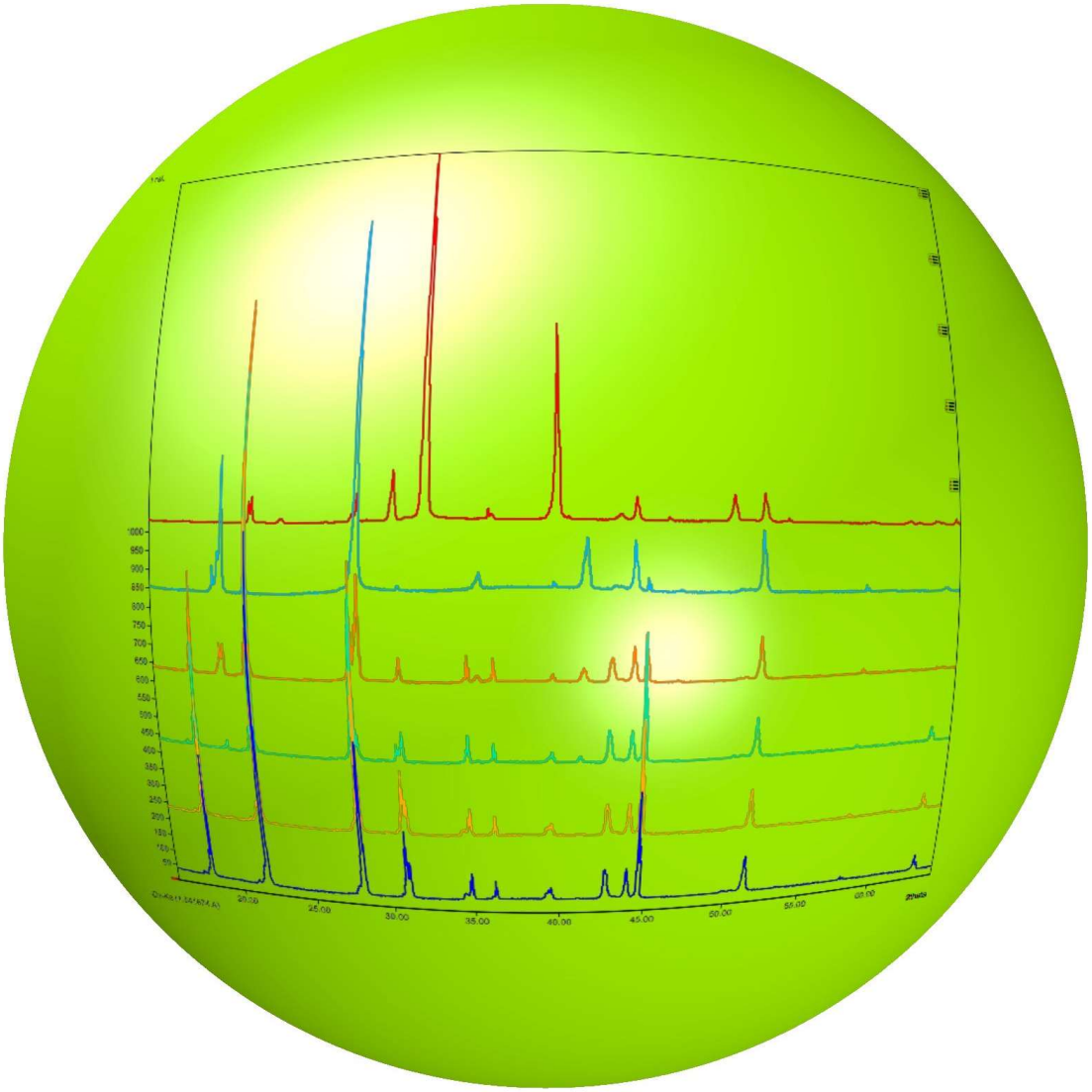
MATCH!

Phase Identification from Powder Diffraction

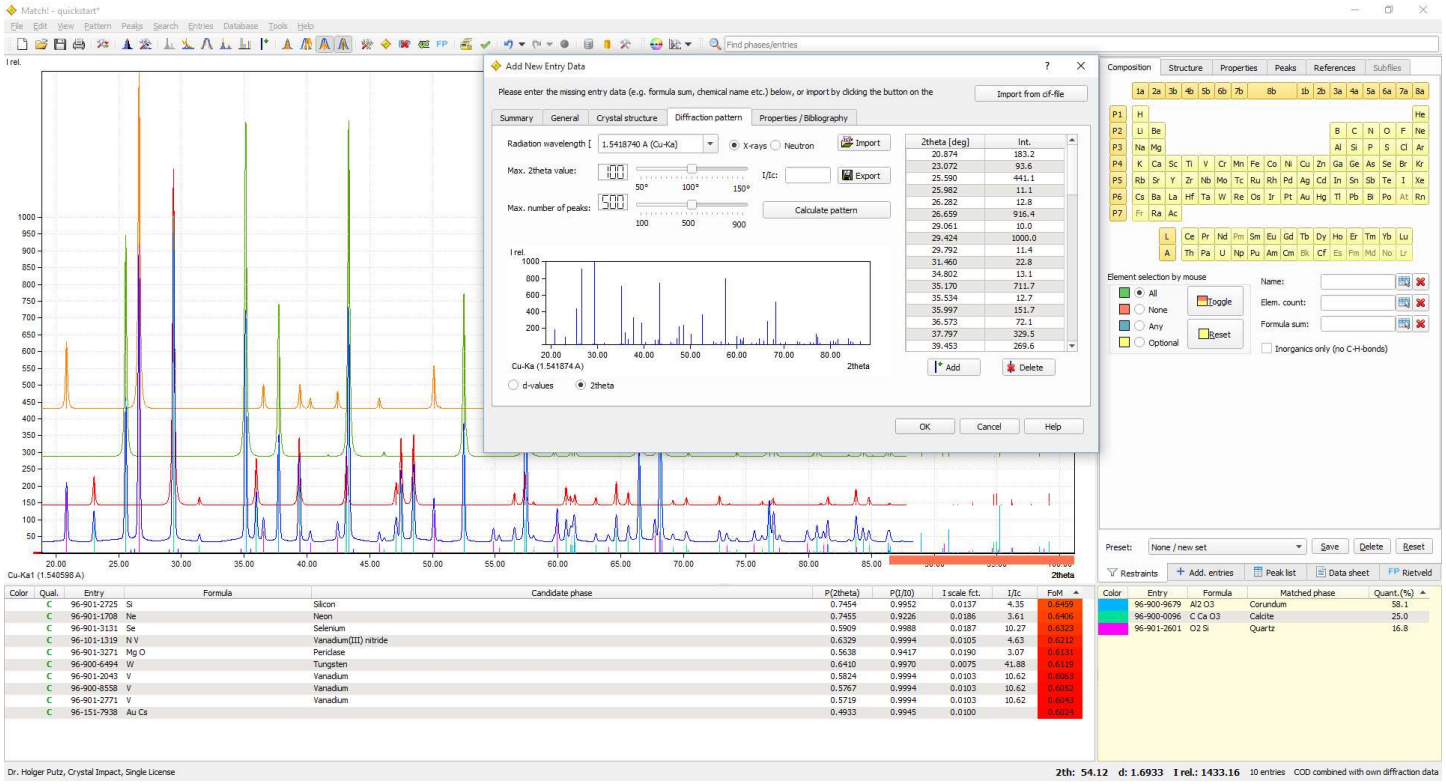


Progress in Phase Identification from Powder

CRYSTAL IMPACT

Match! is an easy-to-use software for phase identification from powder diffraction data. It compares the diffraction pattern of your sample to a database containing reference patterns, in order to identify the phases that are present. Additional knowledge about the sample like known phases, elements or density can be applied easily. In addition to this **qualitative analysis**, a **quantitative analysis** (using Rietveld refinement) can be performed as well.
As reference database, you can apply the included **free-of-charge COD database** and/or any **ICDD PDF** product, use your valid ICSD/Retrieve (-2002) license, and/or **easily add your own diffraction patterns** or crystal structure data.
You can quickly setup and run **Rietveld refinements** from within Match!, with the actual calculations being performed automatically, using the well-known program **FullProf** (by J. Rodriguez-Carvajal) in the background. Match! provides a **gentle introduction into Rietveld refinement**, from fully automatic operation (user-configurable) to the "Expert" mode.
More information and free-of-charge test version:

http://www.crystalimpact.com/match



Feature

- Fast multiple phase identification from powder diffraction data
- Runs on Windows, Mac OS X and Linux
- Use free-of-charge reference patterns calculated from the COD (incl. I/I_c), any ICDD PDF database, your valid licence for ICSD/Retrieve (released 1993-2002) and/or your own diffraction or crystal structure data in phase identification
- Perform Rietveld refinement calculations, e.g. for quantitative analysis, using the well-known FullProf in the background
- Instant usage of additional information (known phases, elements, density, color etc.) using perpetual restrainting
- Automatic residual searching with respect to identified phases
- Automatic raw data processing including peak searching, profile fitting and 2theta error correction
- Comfortable background definition/modification using the mouse
- Convenient editing of peaks (add/shift/delete/fit) using the mouse
- Improved zooming and tracking using mouse or dialog
- Display several piled experimental patterns e.g. for comparison
- Semi-quantitative analysis (Reference Intensity Ratio method)
- Crystallite size estimation based on Scherrer approach
- Large variety of supported diffraction data file formats

System requirements

- **Windows** XP, Vista, Windows 7, Windows 8/8.1 or Windows 10; **Mac OS X** 10.6 "Snow Leopard" or higher; **Linux** (Intel 32- or 64-bit), e.g. openSUSE, Ubuntu, Fedora
- 2 GB of RAM
- 500 MB of free disc space
- **Supported diffraction data file formats (automatic recognition)**: Bruker/Siemens, DBWS, DRON-3, G670, Inel, GNR (formerly Ital Structures), Jade/MDI/SCINTAG, JEOL Export, PANalytical/Philips, Rigaku, SCINTAG, Seifert, Shimadzu, various text files (profile or peak list data), Siemens, Sietronics, Stoe, TXRD export, XPowder

Prices for new

	non-profit org.	profit org.
Single licence	599 €	1,198 €
Site licence**	1,198 €	2,396 €
Campus licence***	2,396 €	4,792 €

* Prices include a 3-year subscription for updates; they do not include taxes that may be due.
** Unlimited number of installations within one institute/dept.
*** Unlimited number of installations within one university/company.

CRYSTAL IMPACT
GbR
Kreuzherrenstr. 102
D-53227 Bonn

Tel: +49 (228) 981 36 43
Fax: +49 (228) 981 36 44
E-mail: info@crystalimpact.com
http://www.crystalimpact.com